

Notice of References Cited

Application/Control No.

10/079,447

Applicant(s)/Patent Under
Reexamination
GABARA ET AL.

Examiner

Granvill D Lee, Jr

Art Unit

2825

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,111,470	08-2000	Dufour, Yves	331/17
	B	US-6,424,022	07-2002	Wu et al.	257/665
	C	US-5,196,920	03-1993	Kumamoto et al.	257/798
	D	US-5,864,311	01-1999	Johnson et al.	341/155
	E	US-5,872,531	02-1999	Johnson et al.	341/110
	F	US-6,586,292	07-2003	Wu et al.	438/215
	G	US-5,475,255	12-1995	Joardar et al.	257/547
	H	US-3,906,174	09-1975	Dotter, Jr., Berton E.	714/715
	I	US-6,330,375	12-2001	Fishman et al.	385/11
	J	US-5,854,600	12-1998	Johnson et al.	341/155
	K	US-2002/0164851	11-2002	Wu et al.	438/215
	L	US-5,640,161	06-1997	Johnson et al.	341/122
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chang et al. "Fully differential current-input CMOS amplifier front-end suppressing mixed signal substrate noise for optoelectronic applications" Circuits and Systems ISCAS Proceedings of the 1999 IEEE International Symposium Vol. 1 30 May 99 Pg 327-30.
	V	Xu et al. "Measuring and modeling the effects of substrate noise on the LNA for a CMOS GPS receiver" IEEE journal of solid-state circuits Vol. 36 no. 3 march 2001 Pg. 473-485.
	W	Heijningen et al. "Substrate noise generation in complex digital system: efficient modeling and simulation methodology and experimental verification" Digest of technical papers Solid state circuits conference)-7803-6608-5 IEEE 2001.Pg. 22.1
	X	Makie-Fukuda "Substrate noise measurement by using noise-selective voltage comparators in analog and digital mixed-signal integrated circuits" IEEE Trans. on instrumentation and measurement Vol. 48 No. 6 Dec. 1999 Pg. 1068-72

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.